



CKET NO: 220033US90

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF: :  
Fuyuhiko INOUE, et al. : EXAMINER: STAFIRA, M. P.  
SERIAL NO.: 10/080,537 :  
RCE FILED: Herewith : GROUP ART UNIT: 2877  
FOR: WAVEFRONT ABERRATION :  
MEASURING METHOD AND  
UNIT, EXPOSURE  
APPARATUS, DEVICE  
MANUFACTURING  
METHOD, AND DEVICE

AMENDMENT

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Notice of Allowance dated March 19, 2004, please amend the  
above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on  
page 31 of this paper.

**Remarks/Arguments** begin on page 41 of this paper.

06/23/2004 HVUON61 00000051 10080537

02 FC:1201  
03 FC:1202

86.00 OP  
198.00 OP